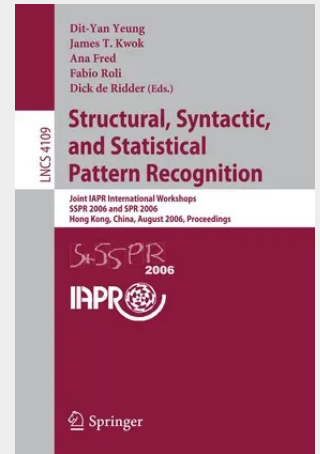


Yeung / Kwok / Fred

Structural, Syntactic, and Statistical Pattern Recognition

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